

Notice of References Cited

Application/Control No.

10/593,772

Applicant(s)/Patent Under
Reexamination
ONO ET AL.

Examiner

GREGORY CLARK

Art Unit

1794

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U.S. PATENT DOCUMENTS

*		Document Number	Date	Name	Classification
		Country Code-Number-Kind Code	MM-YYYY		
	A	US-			
	B	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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